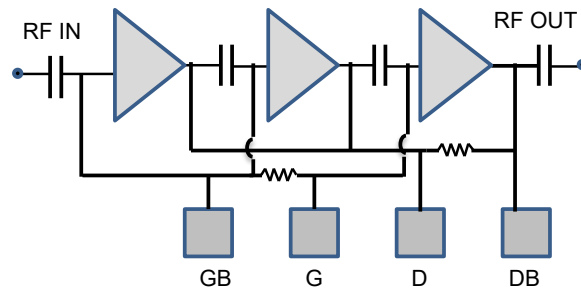
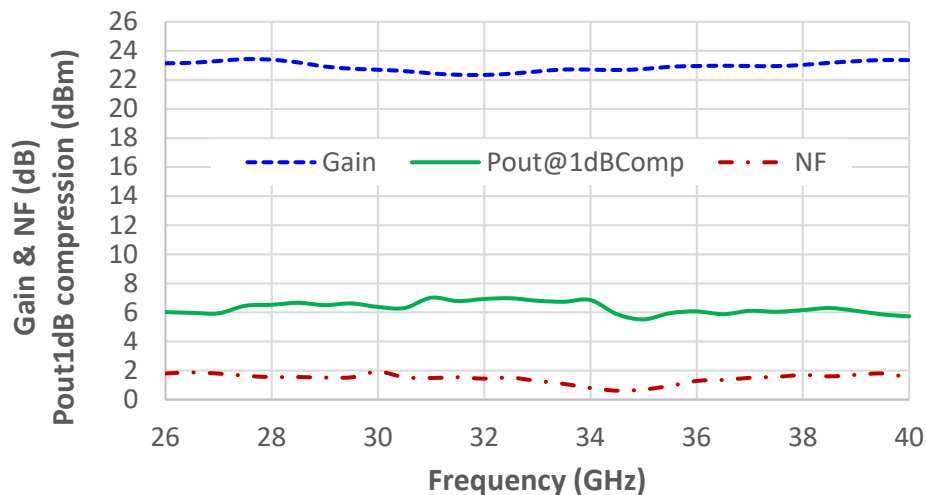


Advanced Information: AI2514

26-40GHz Low Noise Amplifier GaAs Monolithic Microwave IC



The CHA2362-99F is a wide band Low Noise Monolithic Amplifier which integrates three amplification stages that produces 22dB gain associated to 2dB noise figure. It is designed for a wide range of applications, from military to commercial communication systems. The circuit is manufactured with a pHEMT process. It is available in chip form.



Electrical Characteristics

Tbackside= +25°C, Vd = +3.5V

Symbol	Parameter	Min	Typ	Max	Unit
Freq	Frequency range	26		40	GHz
Gain	Linear Gain		22		dB
NF	Noise Figure		2		dB
Op1dB	Output Power @1dB comp.		6.5		dB

Electrical Characteristics

Tbackside= +25°C, Vd = +3.5V, IDq = 65mA

Symbol	Parameter	Min	Typ	Max	Unit
Freq	Frequency range	26		40	GHz
Gain	Linear Gain		22		dB
NF	Noise Figure		2		dB
S11	Input Return loss		13		dB
S22	Output Return loss		13		dB
P1dB	Output power at 1dB gain compression		6.5		dBm
Vd	Drain supply voltage		3.5		V
Id	Drain supply current		65		mA
Vg	Gate supply voltage		-1		V
Ig	Gate supply current		1.3		mA

These values are representative of on-board measurements as defined on the drawing in the Evaluation Board section.

Recommended Operating Range

Tbackside= +25°C

Symbol	Parameter	Values	Unit
Vd	Drain bias voltage	3 to 4	V
Idq	Quiescent current	50 to 70	mA
Vg	Gate bias voltage	-3.0 to +0.10	V
Pin	Maximum peak input power overdrive	+6	dBm
Tj	Maximum junction temperature	175	°C

Absolute Maximum Ratings ⁽¹⁾

Tbackside= +25°C

Symbol	Parameter	Values	Unit
Vd	Drain bias voltage	6	V
Id	Maximum drain current	115	mA
Vg	Gate bias voltage	-3.5 to +0.15	V
Pin	Maximum peak input power overdrive	+15	dBm
Tj	Maximum junction temperature	175	°C
Tstg	Storage temperature range	-55 to +150	°C

⁽¹⁾ Operation of this device above any one of these parameters may cause permanent damage.

Advanced Information

Temperature Range

Symbol	Parameter	Values	Unit
Tbackside	Operating temperature range	-40 to +95	°C
Tstg	Storage temperature range	-55 to +150	°C

Typical Bias Conditions

Tbackside= +25°C

Symbol	Pad Number	Description	Values	Unit
D & DB	V1	DC drain voltage	3.5	V
GB	V2	DC gate voltage	-1	V

“Power ON” Sequence

1. Bias LNA gate voltage at Vg close to Vpinch-off (Typically: Vg ≈ -3.0V)
2. Apply Vd bias voltage (Typically: Vd = 3.5V)
3. Increase gate voltage Vg up to quiescent bias drain current Idq
4. Apply RF signal

“Power OFF” Sequence

1. Turn off RF signal
2. Bias LNA gate voltage at Vg close to Vpinch-off (Typically: Vg ≈ -3.0V)
3. Check that quiescent bias drain current Idq is close to 0mA
4. Turn Vd bias voltage to 0V
5. Check that quiescent bias drain current Idq is close to 0mA
6. Turn Vg bias voltage to 0V

Advanced Information

Typical on-wafer Sij parameters

Tbackside= +25°C Vd = +4.0V Id = 65mA

Freq (GHz)	S11 (dB)	PhS11 (°)	S12 (dB)	PhS12 (°)	S21 (dB)	PhS21 (°)	S22 (dB)	PhS22 (°)
0.50	-0.27	-18.21	-79.13	37.46	-41.59	-146.41	-0.74	-32.15
2.00	-0.99	-66.56	-95.05	-70.89	-39.27	57.84	-1.52	-107.05
3.00	-1.51	-92.01	-72.44	-46.53	-42.60	38.08	-2.47	-143.25
8.00	-2.31	-167.37	-76.88	-160.56	-41.61	4.96	-12.61	147.36
9.00	-2.28	-178.13	-81.46	-120.67	-34.30	1.29	-13.20	154.62
10.00	-2.27	171.38	-73.67	-166.25	-29.11	-13.67	-12.98	155.41
11.00	-2.28	160.78	-69.91	160.92	-25.00	-26.21	-12.98	152.92
12.00	-2.37	150.20	-65.68	151.74	-20.85	-35.98	-13.22	149.59
13.00	-2.41	138.43	-65.49	115.65	-16.45	-47.01	-12.94	144.60
14.00	-2.52	125.99	-64.51	84.00	-11.70	-61.10	-12.87	136.77
15.00	-2.67	112.54	-63.02	78.62	-6.86	-79.63	-13.07	126.04
16.00	-3.07	98.16	-66.60	67.89	-2.31	-102.48	-13.41	113.86
17.00	-3.71	83.13	-72.67	105.54	1.87	-129.23	-14.03	99.41
18.00	-4.44	67.41	-67.72	155.42	5.41	-157.95	-15.03	80.11
19.00	-5.25	50.94	-60.10	133.34	8.56	172.98	-16.06	55.35
20.00	-6.10	31.95	-56.53	112.82	11.51	143.67	-16.94	24.10
21.00	-6.93	10.11	-53.14	85.35	14.29	113.60	-17.08	-13.33
22.00	-7.68	-14.41	-50.66	70.96	16.89	82.02	-16.08	-50.29
23.00	-8.57	-43.78	-48.88	44.11	19.24	48.42	-15.26	-82.36
24.00	-9.40	-77.72	-47.37	18.87	21.17	12.77	-15.06	-109.91
25.00	-10.13	-114.49	-46.32	-7.76	22.54	-23.93	-15.73	-130.41
26.00	-10.94	-150.06	-46.51	-41.85	23.31	-60.23	-17.10	-137.26
27.00	-11.70	174.07	-46.44	-68.32	23.61	-94.84	-17.34	-136.58
27.50	-11.90	157.53	-47.02	-74.64	23.63	-111.18	-16.67	-139.01
28.00	-12.29	143.24	-46.81	-94.89	23.60	-126.77	-15.84	-140.43
29.00	-12.82	114.49	-47.89	-120.05	23.51	-156.51	-14.52	-152.66
30.00	-13.59	86.30	-49.08	-143.53	23.32	175.20	-14.16	-167.21
31.00	-14.17	58.25	-49.21	-169.71	23.19	148.18	-14.40	172.80
32.00	-14.26	34.04	-49.00	167.42	23.03	122.29	-14.94	151.31
33.00	-14.47	11.70	-49.44	145.78	22.95	96.72	-16.39	122.12
34.00	-14.75	-4.69	-48.69	121.31	22.88	71.51	-17.25	88.12
35.00	-15.07	-19.98	-48.81	104.17	22.84	46.29	-16.51	49.21
36.00	-15.14	-32.58	-49.05	90.88	22.78	21.34	-14.78	15.33
37.00	-15.42	-39.74	-48.44	75.84	22.77	-3.87	-13.00	-12.54
38.00	-16.27	-44.09	-47.10	55.03	22.86	-29.24	-11.67	-35.00
39.00	-16.12	-44.55	-46.45	39.31	22.88	-56.30	-10.84	-53.79
40.00	-15.95	-40.00	-46.47	19.63	23.02	-84.39	-10.83	-68.08
41.00	-14.33	-33.13	-47.15	1.80	23.17	-116.09	-12.16	-73.39
42.00	-11.91	-29.04	-46.61	-24.80	22.89	-154.02	-13.01	-49.86

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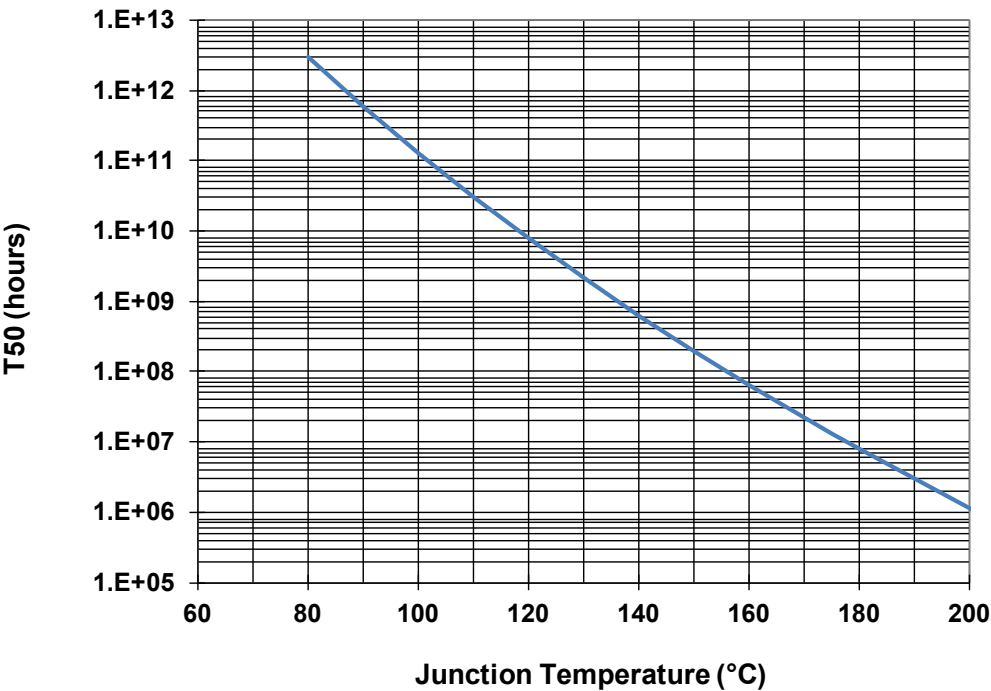
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Device Thermal Performance

All the figures given in this section are obtained assuming that the die is only cooled down by conduction through the chip backside.
The temperature is monitored at the chip back-side interface (Tbackside).
For nominal operating, the system maximum temperature must be adjusted in order to guarantee that Tjunction remains below the maximum value specified in the Recommended Operating Ratings table.
So, the system PCB must be designed to comply with this requirement.

Parameter	Conditions	Tjunction (°C)	Rth (°C/W)	T50 (hours)
Rth ⁽¹⁾ Thermal Resistance	Vd = 4V Idq = 65mA Dissipated power = 0.263W	91	20.5	5E10 ¹¹

(1) Thermal resistance measured to backside of the chip with Tbackside=85°C



Advanced Information

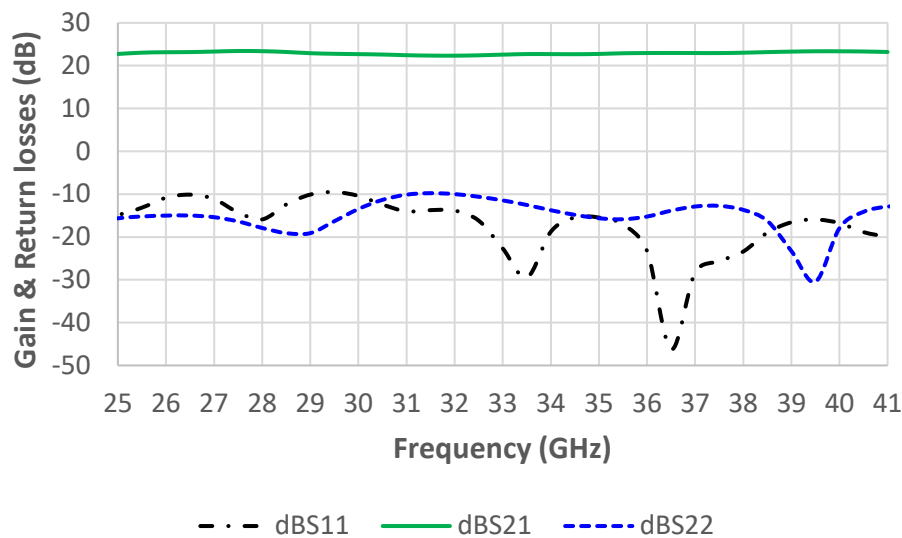


Typical Board Measurements

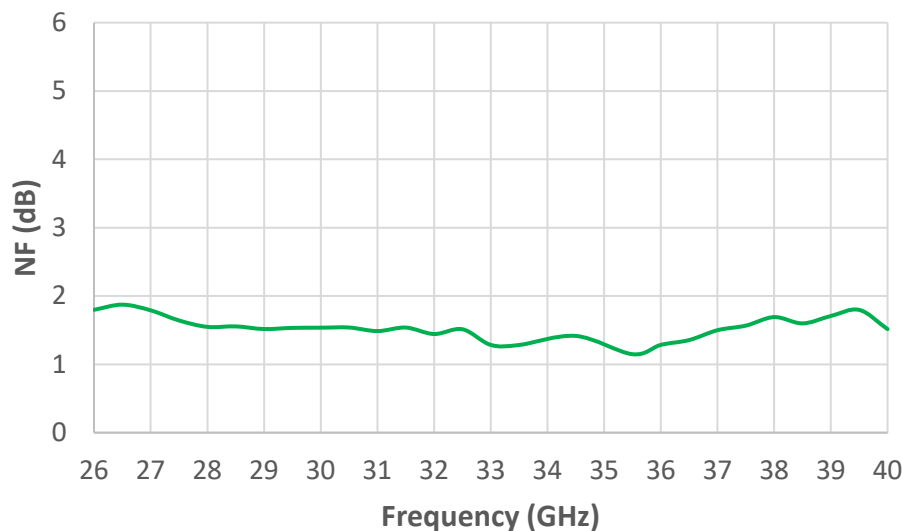
Tbackside = 25°C, Vd = 3.5V, IDq = 65mA

The following values are representative of on board measurements, on die access reference planes.

Gain and Return losses vs. Frequency



Noise Figure vs. Frequency

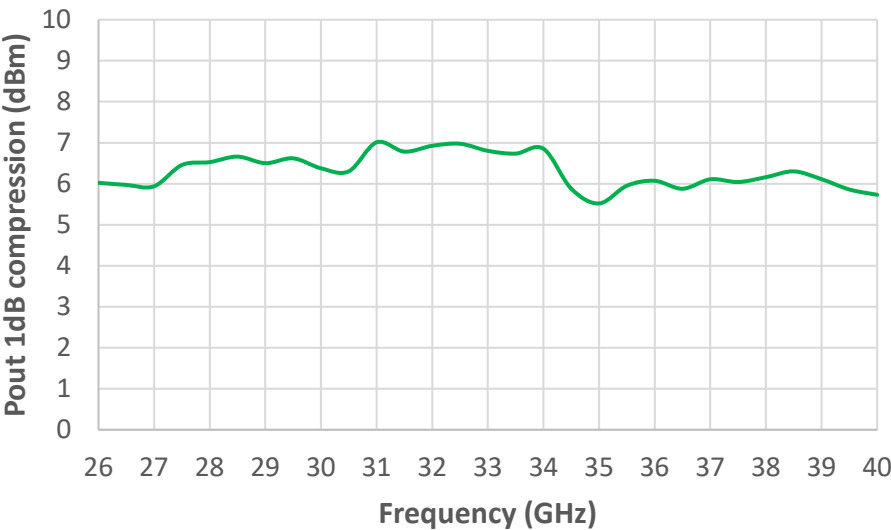


Advanced Information

Typical Board Measurements

Tbackside = 25°C, Vd = 3.5V, IDq = 65mA
The following values are representative of on board measurements, on die access reference planes.

Output power at 1 dB gain compression vs. Frequency



Advanced Information

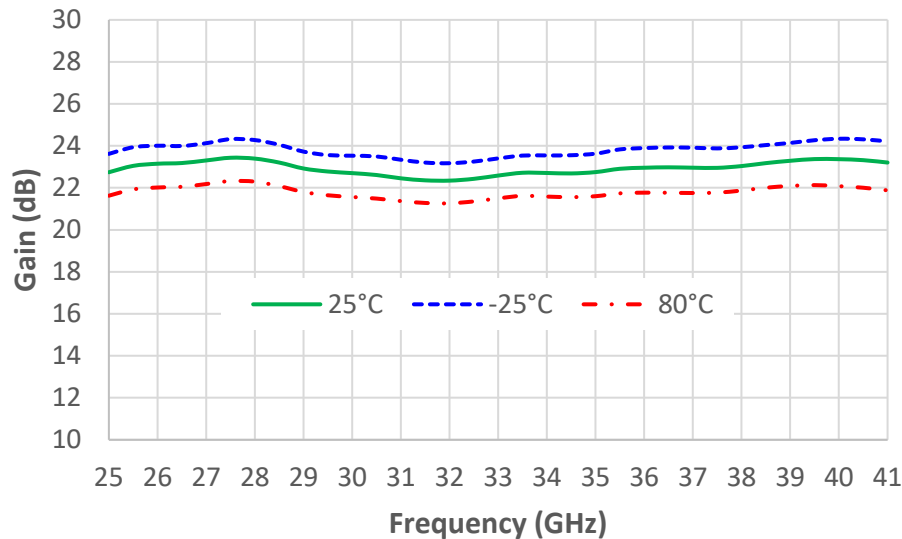


Typical Board Measurements

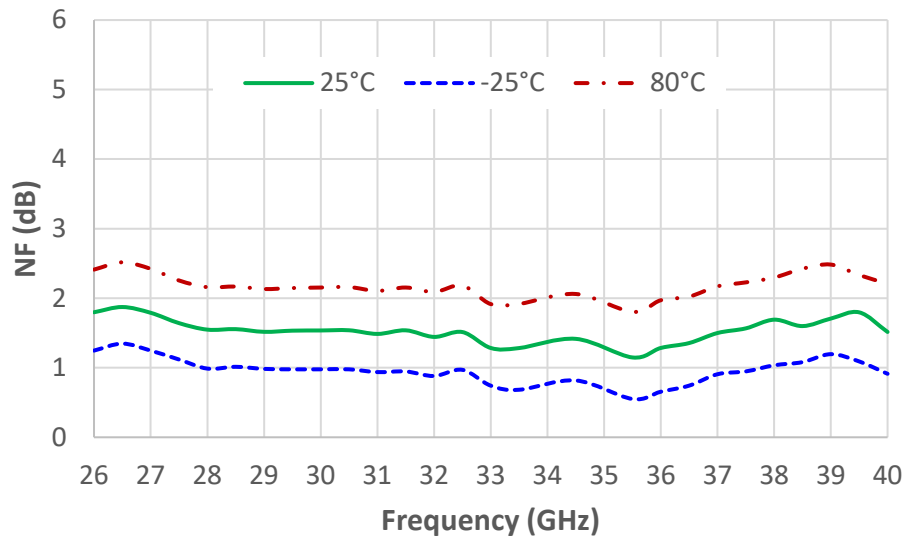
Tbackside = 25°C, Vd = 3.5V, IDq = 65mA

The following values are representative of on board measurements, on die access reference planes.

Linear Gain vs. Temperature



Noise Figure vs. Temperature



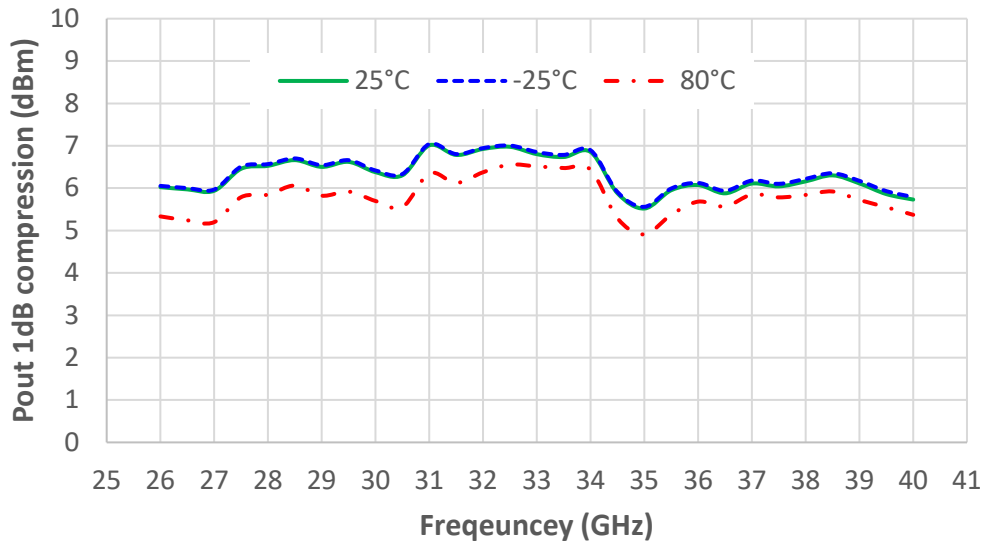
Advanced Information

Typical Board Measurements

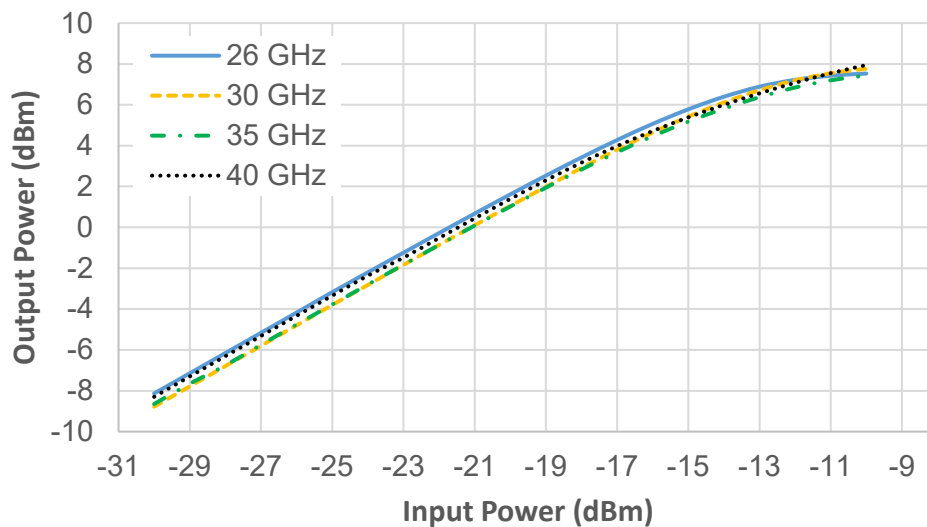
Tbackside = 25°C, Vd = 3.5V, IDq = 65mA

The following values are representative of on board measurements, on die access reference planes.

Output power at 1dB compression vs. Temperatures



Output power vs. Input power



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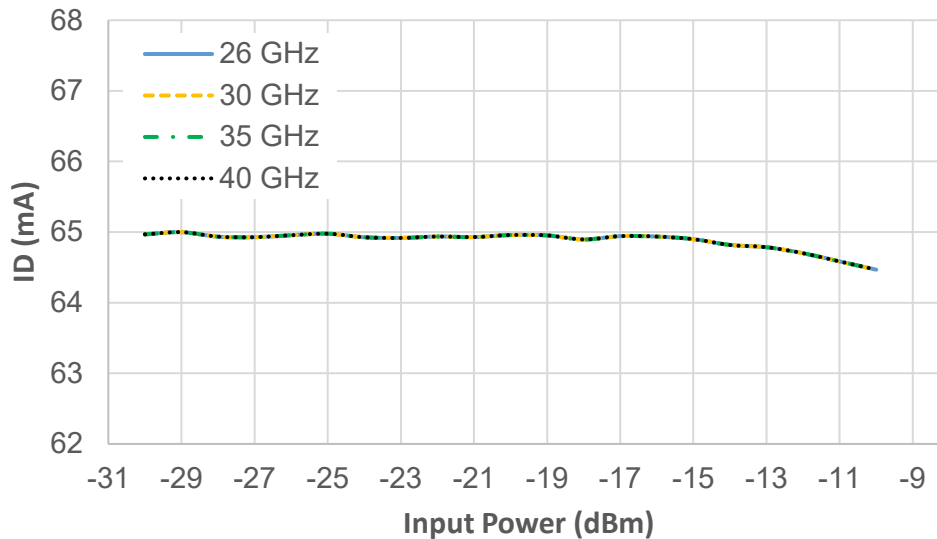


Typical Board Measurements

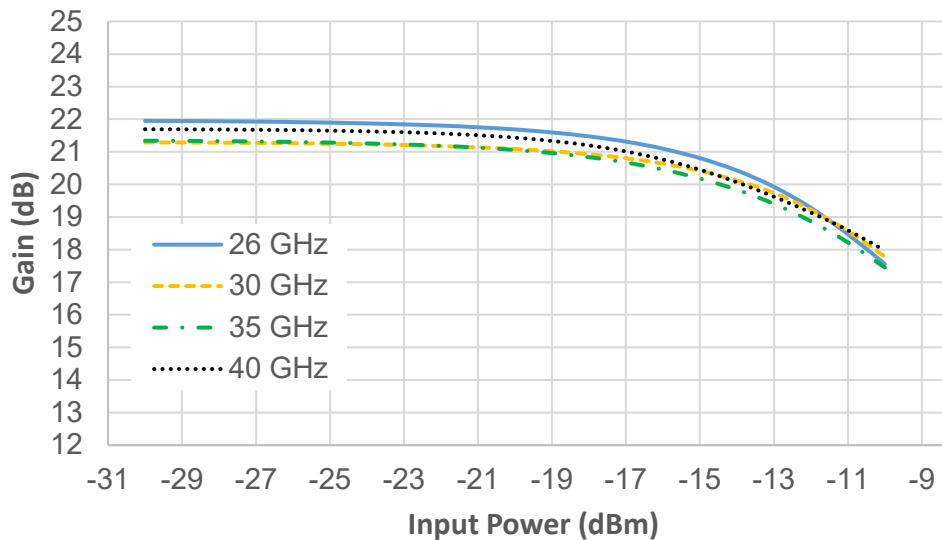
Tbackside = 25°C, Vd = 3.5V, IDq = 65mA

The following values are representative of on board measurements, on die access reference planes.

ID vs. Input power

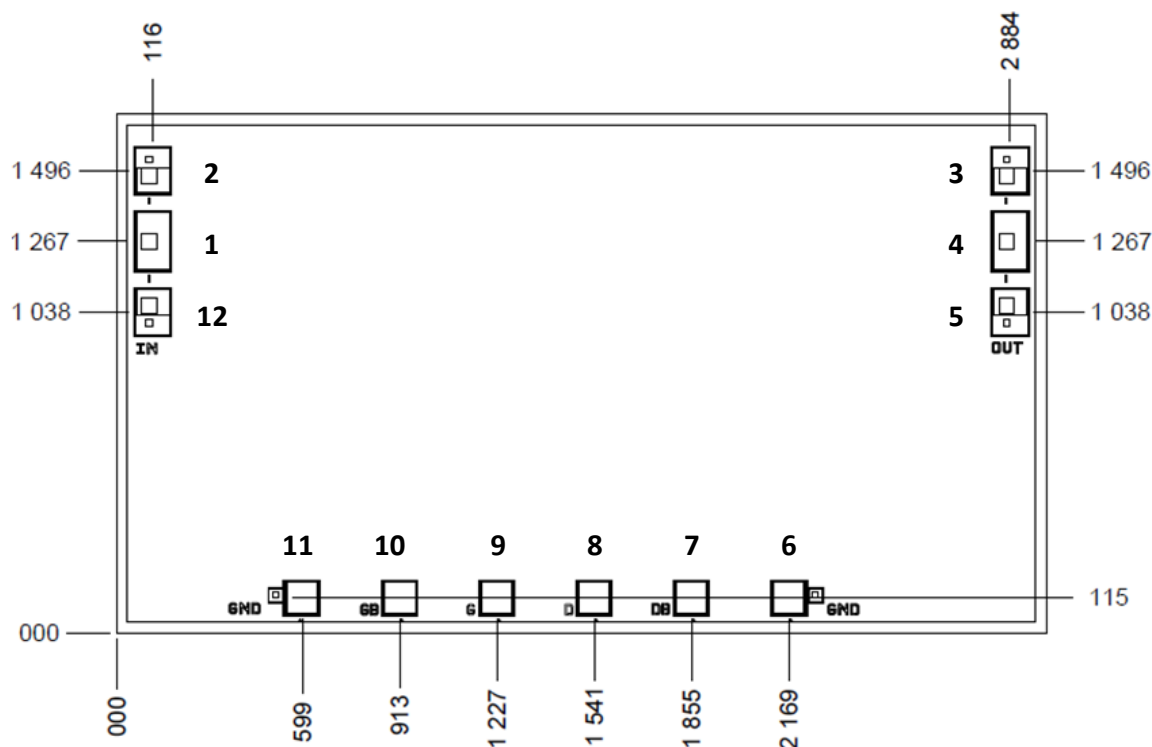


Gain vs. Input power



Advanced Information

Mechanical data



Chip thickness: 70μm

Chip size:3000/1680 ±35μm

All dimensions are in micrometers

RF Pads (1,2) = 192 x 114 μm

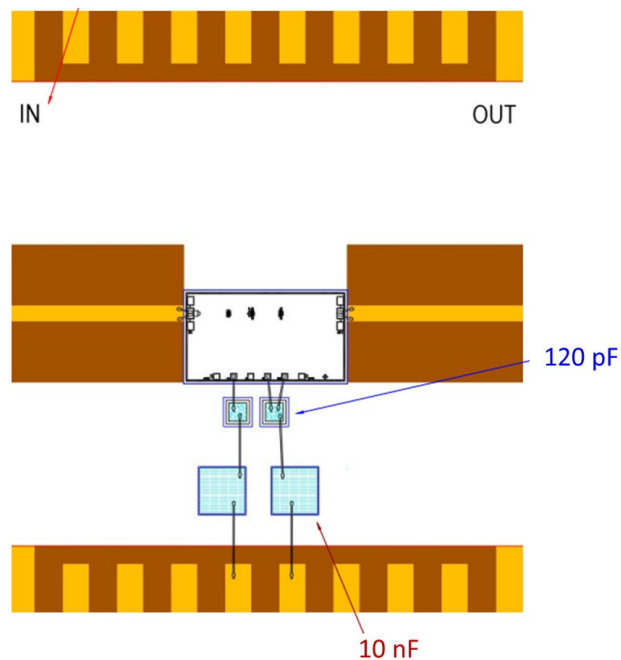
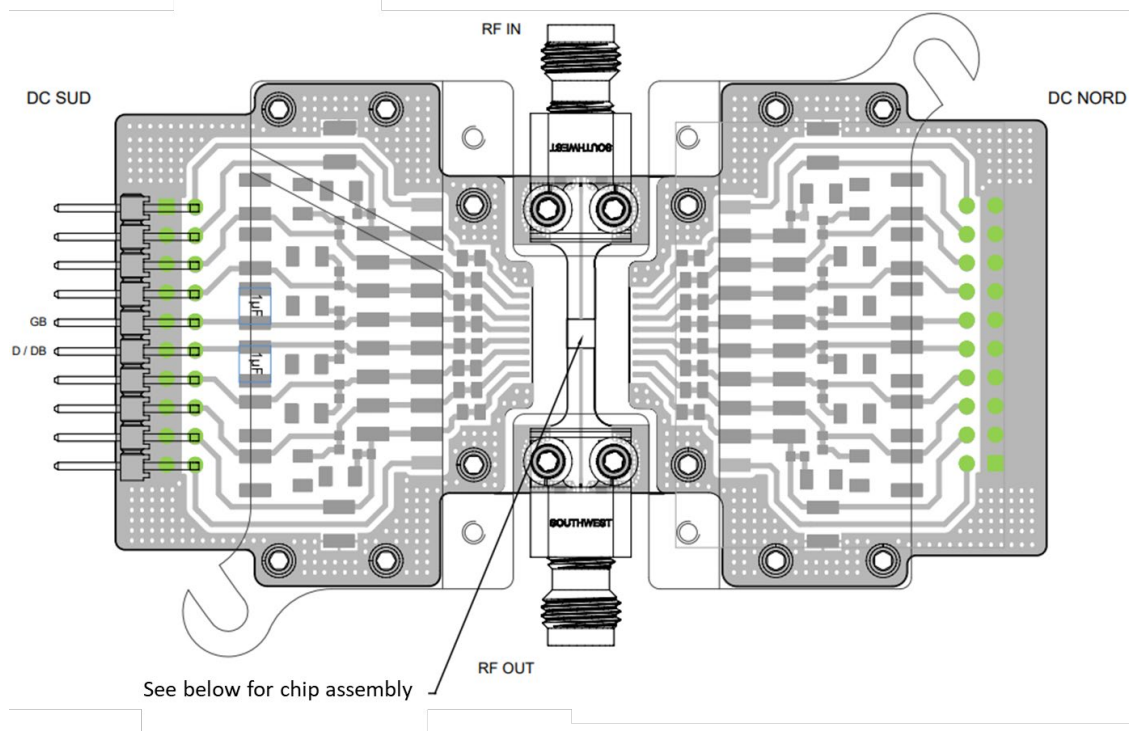
DC Pads = 106 x 106 μm

PAD Number⁽¹⁾	Name	Description
1	RF IN	Input RF port
4	RF OUT	Output RF port
2,3,5,6,11,12	GND	ground
10	GB	DC Gate voltage
7,8	DB, D	DC Drain voltage

(1) Pad number 9: G is not used

Advanced Information

Evaluation board



Total of 3 levels of decoupling capacitor have been used, 2 levels on the tab and 1 level on the board. The first level is composed of 120 pF chip capacitors, the second level is composed of 10nF chip capacitors, the third level is composed of 1µF. The first two levels should be as close as possible to the die.

Advanced Information

Recommended reflow process assembly

Refer to the application note AN0001 available at <https://www.ums-rf.com> for die attach.

Recommended ESD management

Refer to the application note AN0020 available at <https://www.ums-rf.com> for ESD sensitivity and handling recommendations.

Recommended Evaluation board assembly

Refer to the application note AN0030 available at <https://www.ums-rf.com> Evaluation board.

Recommended environmental management

UMS products are compliant with the regulation in particular with the directives RoHS N°2011/65 and REACH N°1907/2006. More environmental data are available in the application note AN0019 also available at <http://www.ums-rf.com>.

Maturity Level

Maturity Level	Product status	Documentation	Reliability	Usage in a system
Lab Sample (LS)	Decision to develop the product is not confirmed	Technical Information	No commitment	Lab demonstrator
Engineering Sample (ES)	Design may change	Advanced Information	The design is within the recommended temperature, current and voltage ranges as regards the technology used.	Engineering demonstrator
Product Representative Unit (PRU)	Design is frozen	Data-sheet	Tests results are available on the foreseen product or on an similar one	Production

Sampling request reference

Die: ES-CHA2362-99F
Demo board: EVB-CHA2362-99F

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